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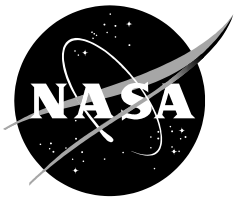

Single-Event Effects Test Report Texas Instruments, OPA855 Low-Noise Operational Amplifier

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November 2022

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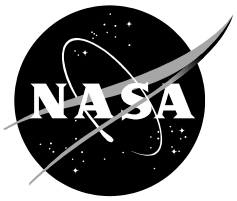

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Test Date: 11/11/2022
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November 2022

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1. Introduction and Purpose

Testing was done to characterize the Texas Instruments Operational Amplifiers OPA855 single event effects (SEE) response. The primary SEE concerns for this device are single event latchup (SEL) and single event transients (SETs). Testing focused on determining susceptibility to SEL and characterizing the SET response. Testing occurred on November 11, 2022.

2. Device Description

The OPA855 is a wideband, low-noise operational amplifier with bipolar inputs for wideband transimpedance and voltage amplifier applications. When the device is configured as a transimpedance amplifier (TIA), the 8-GHz gain bandwidth product (GBWP) enables high closed-loop bandwidths at transimpedance gains of up to tens of kΩs. Four (4) parts were delidded and available for SEE testing. All specifications and descriptions are according to the datasheet. More information can be found in Table 1.

Table I. Part description

Part Number	OPA855
Manufacturer	Texas Instruments
Quantity Tested	4
Part Function	Wideband Operational Amplifier
Part Technology	BiCMOS
Package	8SWON

3. Test Setup

Table II. Pinout guide for OPA855

Pinout	Function
1	Feedback
2	No connection
3	Inverting input
4	Noninverting input
5	$-V_s$
6	Output
7	$+V_s$
8	Power down

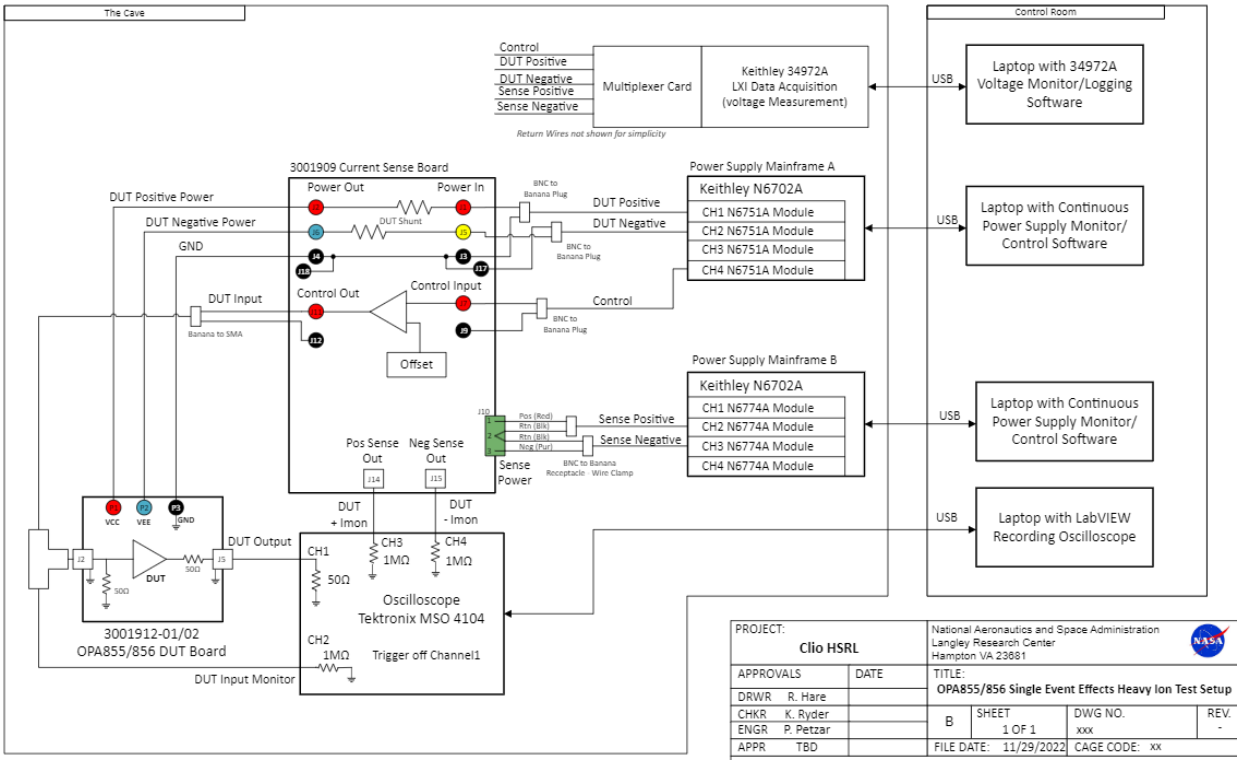

Figure 1. Test setup for the OPA855.

4. Test Facility

Facility:	Lawrence Berkeley Nation Laboratory's 88" Cyclotron facility
Type of Radiation:	Heavy ions
Facility Configuration:	16 MeV/amu tune
Flux:	Varied between 2.9×10^{3} and 1.1×10^{5} $cm^{-2}\cdot s^{-1}$
Fluence:	A total effective fluence of 1×10^{7} cm^{-2} was achieved for each run to screen for destructive SEL.
Beams / LET:	Ag was used during testing at 42.34°, 45°, and 60°. This provided a range of LETs from 66.9 to 104 $MeV\cdot cm^{2}/mg$.

5. Test Conditions

Temperature:	26 °C, 30 °C, 35 °C, 55 °C, 88 °C
In-Air or Vacuum:	In-air
Supply Voltage:	±2.5 V
Input Voltage	0 V, floating

6. Test Methods

The operation amplifier was powered with a nominal supply voltage of ±2.5 V and an input voltage of either 0 V or floating. The nominal supply current during testing was 80 mA and was monitored during testing for SEL. The amplifier's output voltage was monitored for SETs using an oscilloscope, which saved the waveforms of any observed SET. Elevated temperatures were used during SEL testing. If SEEs were observed, they were counted and recorded in the run log.

6.1. Single-Event Transients

SETs in the operational amplifier manifest as self-recovering changes in the output voltage. SETs can be either positive-going, negative-going, or have more complex features, and can be as large as the rail-to-rail voltage. The oscilloscope was used to observed and count all SETs with an amplitude above the nominal noise floor were observed (between 0.08 V and 0.7 V). The counts were recorded in the run log and waveforms were captured by the oscilloscope.

6.2. Single-Event Latchup

SEL occurs when the supply current instantaneously increases to the compliance current set on the power supplies and is sustained until power is cycled. If SEL occurred the run was ended, and the operational amplifier was power cycled. SEL count was recorded in the run log.

7. Test Procedure

Testing was completed to an effective fluence of at least 1×10^{7} cm^{-2} at LETs between 66.9 and 104 MeV·cm^2/mg to screen for SEL. SETs were observed and captured during these runs.

8. Data Requirements

The counts for SET and SEL were recorded by on-site personnel during testing and stored in the run log. Supply current was monitored and recorded by the power supplies and the oscilloscope captured any SETs. Relevant facility date (e.g., flux, fluence, LET, ion, air gap, angle, electrical setup) was recorded in real time and stored in the run log.

9. Equipment List

Table III. Equipment List

Manufacturer and P/N	Function	S/N or ECN
Agilent N6702A	Power supply	M161871
Agilent N6702A0	Power supply	M163374
Tektronix MSO5104	Oscilloscope	B010131

10. Run Log

Table IV. Run Log

Run #	Ion	Surface LET (MeV·cm^2/mg)	Temp (°C)	Air Gap (cm)	Angle (°)	Eff. LET (MeV·cm^2/mg)	Avg. Flux (cm^{-2}·s^{-1})	Fluence (cm^{-2})	Eff. Fluence (cm^{-2})
1	Ag	39.17	26	7.62	45	73.5	2.9E+03	8.2E+05	5.8E+05
2	Ag	39.17	88	7.62	45	73.5	1.02E+05	1.4E+07	1.0E+07
3	Ag	39.17	88	5.715	42.34	66.9	1.01E+05	1.4E+07	1.0E+07
4	Ag	39.17	88	5.715	42.34	66.9	1.03E+05	1.4E+07	1.0E+07
5	Ag	39.17	88	5.715	42.34	66.9	1.01E+05	1.4E+06	1.0E+06
6	Ag	39.17	88	5.715	42.34	66.9	1.06E+05	1.4E+07	1.0E+07
7	Ag	39.17	85	5.715	45	69.9	9.85E+04	1.4E+07	1.0E+07
8	Ag	39.17	85	5.715	45	69.9	9.61E+04	1.4E+07	1.0E+07
31	Ag	39.17	30	5.715	45	69.9	1.09E+05	1.4E+07	1.0E+07
32	Ag	39.17	35	5.715	45	69.9	8.45E+04	1.4E+07	1.0E+07
33	Ag	39.17	55	7.62	60	104	1.02E+05	2.0E+07	1.0E+07

11. Results

11.1. Single-Event Latchup

SEL was not observed during testing at any of the test conditions, including elevated temperature and an LET of 104 MeV·cm^2/mg up to an effective fluence of 1.0×10^7 cm^{-2}.

11.2. Single-Event Transients

SETs were observed in the operational amplifier. All test conditions resulted in SET cross-sections on the order of 10^{-6} to 10^{-5} cm^2. Both positive-going and negative-going transients were observed during testing. Runs 5 – 7 observed negative going transients with an input voltage of 0 V. Figure 2 shows a transient with the longest observed duration of ~0.1 – 0.14 µs. Figure 3 shows a transient with a maximum negative amplitude of 1.0 V below the nominal voltage.

Runs 31 and 32 observed positive and negative going transients with a floating input voltage and an LET of 69.9 MeV MeV·cm^2/mg. The floating input voltage was used to remove noise from the output voltage signal. Figure 4 shows a negative-going transient with the maximum observed negative amplitude of 1.0 V below nominal voltage. Figure 5 shows a positive-going transient with the maximum observed positive amplitude of 1.5 V above nominal voltage and maximum observed duration of ~50 ns.

Run 33 was taken at a very deep angle to achieve an LET of 104 MeV·cm^2/mg with a floating input voltage. Negative and positive transients were observed. Figure 6 shows a bipolar transient with the maximum observed negative amplitude of -1.0 V. Figure 7 shows a positive-going transient with a maximum positive amplitude of 1.5 V and a duration of ~60 ns.

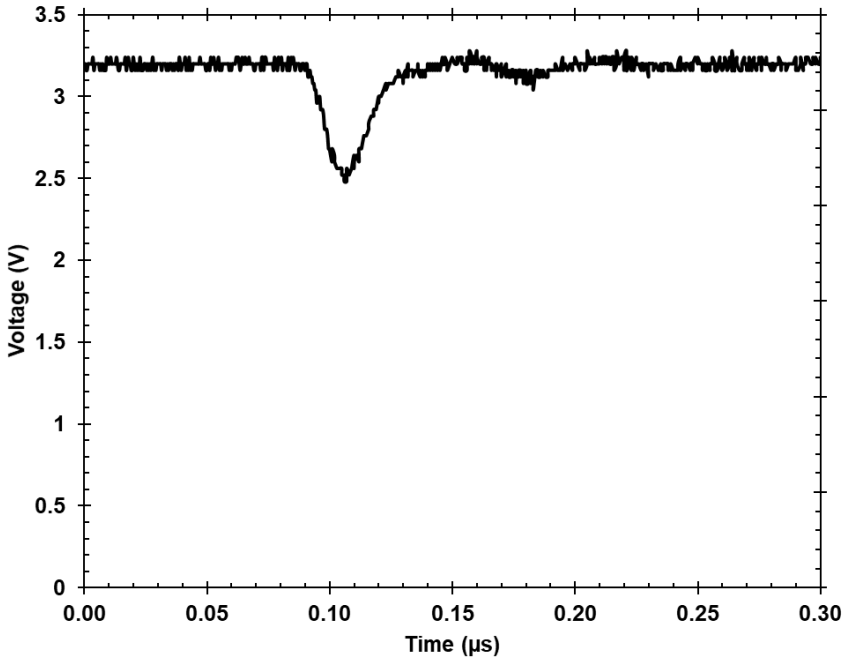

Figure 2. Example of a negative-going SET with maximum observed duration.

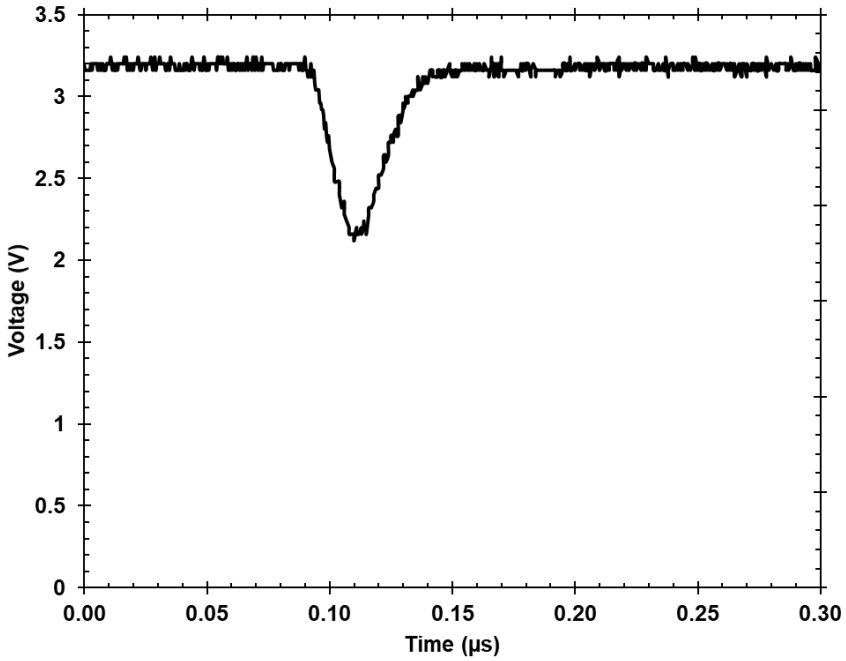

Figure 3. Example of a negative-going SET with the maximum observed negative amplitude.

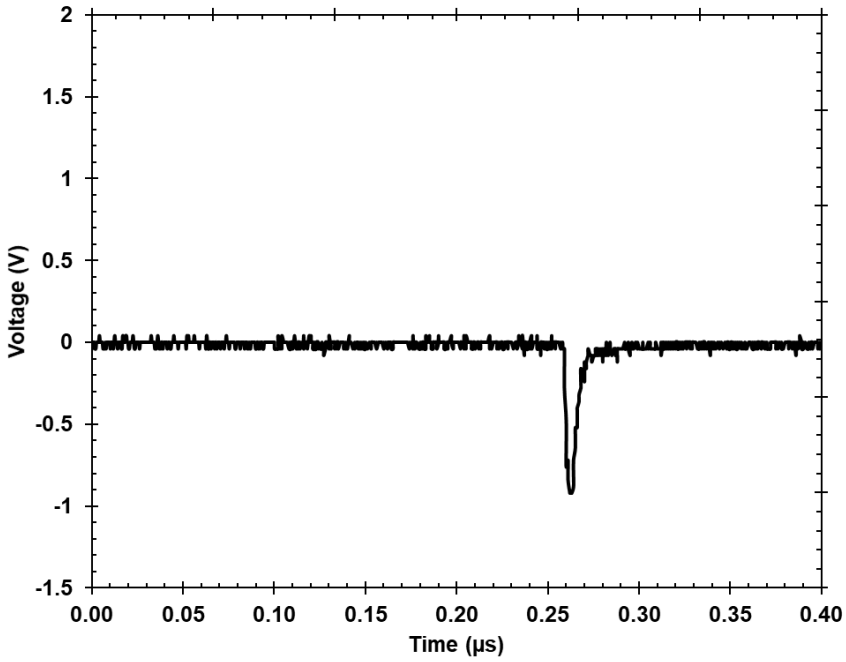

Figure 4. Example of a negative-going SET with the maximum observed negative amplitude.

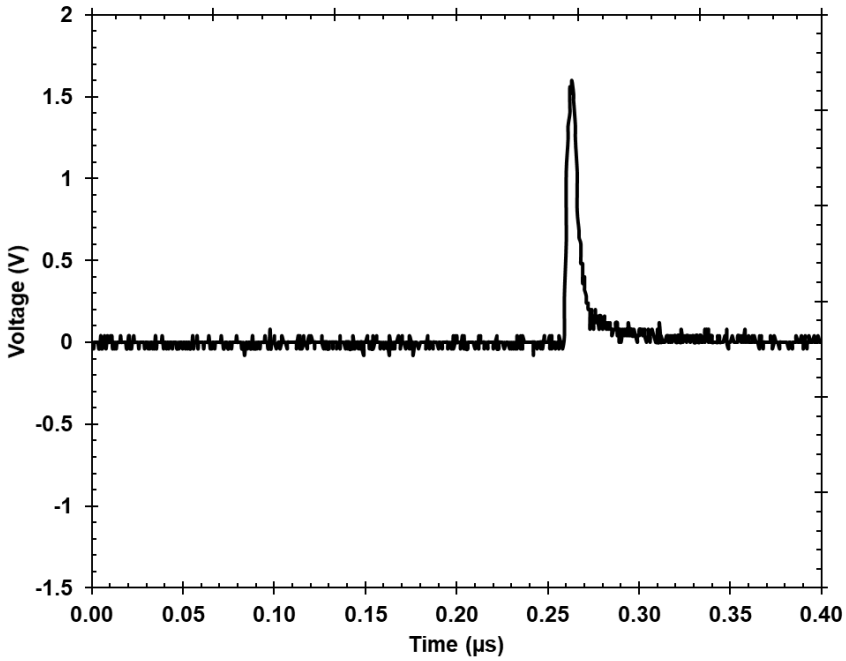

Figure 5. Example of a positive-going SET with the maximum observed positive amplitude and duration

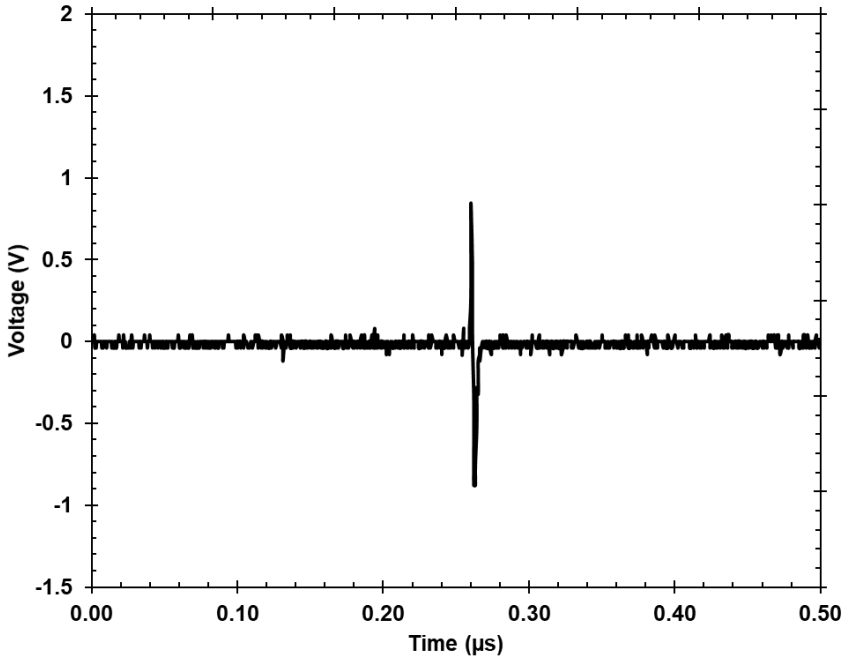

Figure 6. Example of a bipolar SET with the maximum observed negative amplitude.

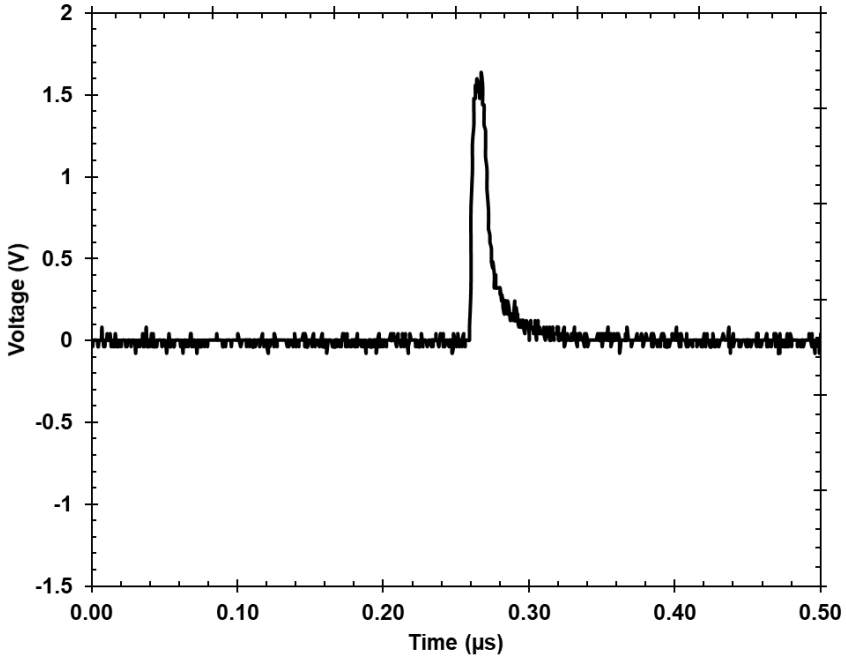

Figure 7. Example of a positive going SET with the maximum observed positive and amplitude and duration.